

The demographic information provides a unique set of data on selected characteristics for the civilian noninstitutional population. Some of the demographic information we collect is age, marital status, gender, Armed Forces status, education, race, origin, and family income. We use these data in conjunction with other data, particularly the monthly labor force data, as well as periodic supplement data. We use these data also independently for internal analytic research and for evaluation of other surveys. In addition, we need these data to correctly control estimates of other characteristics to the proper proportions of age, gender, race, and origin.

We use the data from the CPS on household size and composition, age, education, ethnicity, and marital status to compile monthly averages or other aggregates for national and subnational estimates. We use these data in four principal ways: In association with other data, such as monthly labor force or periodic supplement publications; for internal analytic research; for evaluation of other surveys and survey results; and as a general purpose sample and survey.

Affected Public: Individuals or households.

Frequency: Monthly.

Respondent's Obligation: Voluntary.

Legal Authority: Title 13, United States Code, Section 182.

OMB Desk Officer: Susan Schechter, (202) 395-5103.

Copies of the above information collection proposal can be obtained by calling or writing Diana Hynek, Departmental Paperwork Clearance Officer, (202) 482-0266, Department of Commerce, room 6625, 14th and Constitution Avenue, NW, Washington, DC 20230 (or via the Internet at dhynek@doc.gov).

Written comments and recommendations for the proposed information collection should be sent within 30 days of publication of this notice to Susan Schechter, OMB Desk Officer either by fax (202-395-7245) or e-mail (susan_schechter@omb.eop.gov).

Dated: April 15, 2005.

Madeleine Clayton,

Management Analyst, Office of the Chief Information Officer.

[FR Doc. 05-7779 Filed 4-18-05; 8:45 am]

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DEPARTMENT OF COMMERCE

Foreign-Trade Zones Board

[T-1-2005]

Foreign-Trade Zone 61 San Juan, Puerto Rico, Application for Temporary/Interim Manufacturing Authority, Shell Chemicals Yabucoa, Inc., (Petrochemical Complex), Notice of Approval

On February 11, 2005, an application was filed by the Executive Secretary of the Foreign-Trade Zones (FTZ) Board by the Puerto Rico Trade and Exports Company, grantee of FTZ 61, requesting temporary/interim manufacturing (T/IM) authority for certain petroleum and petrochemical products within Subzone 61L, at the Shell Chemicals Yabucoa, Inc. petrochemical complex in Yabucoa, Puerto Rico.

The application has been processed in accordance with T/IM procedures, as authorized by FTZ Board Order 1347, including notice in the **Federal Register** inviting public comment (70 FR 9614-9615, 2/28/05). The FTZ staff examiner reviewed the application and determined that it meets the criteria for approval under T/IM procedures. Pursuant to the authority delegated to the FTZ Board Executive Secretary in Board Order 1347, the application is approved, effective this date, until April 11, 2007, subject to the FTZ Act and the Board's regulations, including Section 400.28.

Dated: April 11, 2005.

Dennis Puccinelli,

Executive Secretary.

[FR Doc. 05-7792 Filed 4-18-05; 8:45 am]

BILLING CODE: 3510-DS-S

DEPARTMENT OF COMMERCE

International Trade Administration

Johns Hopkins University, School of Medicine, et al., Notice of Consolidated Decision on Applications for Duty-Free Entry of Electron Microscopes

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 A.M. and 5:00 P.M. in Suite 4100W, Franklin Court Building, U.S. Department of Commerce, 1099 14th Street, NW, Washington, D.C.

Docket Number: 05-011. Applicant: Johns Hopkins University, School of Medicine, Baltimore, MD 21205. Instrument: Electron Microscope, Model

H-7600-I. Manufacturer: Hitachi High-Technologies Corporation, Japan. Intended Use: See notice at 70 FR 13011, March 17, 2005. Order Date: July 27, 2004.

Docket Number: 05-013. Applicant: National Institute of Standards and Technology, Gaithersburg, MD 20899. Instrument: Electron Microscope, Model Nova 600 Nanolab. Manufacturer: FEI Company, The Netherlands. Intended Use: See notice at 70 FR 13011, March 17, 2005. Order Date: September 23, 2004.

Comments: None received. Decision: Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as these instruments are intended to be used, was being manufactured in the United States at the time the instruments were ordered. Reasons: Each foreign instrument is an electron microscope and is intended for research or scientific educational uses. We know of no electron microscope, or any other instrument suited to these purposes, which was being manufactured in the United States either at the time of order of each instrument OR at the time of receipt of application by U.S. Customs and Border Protection.

Gerald A. Zerdy,

Program Manager Statutory Import Programs Staff.

[FR Doc. E5-1846 Filed 4-18-05; 8:45 am]

BILLING CODE 3510-DS-S

DEPARTMENT OF COMMERCE

International Trade Administration

University of Chicago, Notice of Decision on Application for Duty-Free Entry for Scientific Instrument

This decision is made pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 A.M. and 5:00 P.M. in Suite 4100W, U.S. Department of Commerce, Franklin Court Building, 1099 14th Street, NW, Washington, D.C.

Docket Number: 05-012. Applicant: University of Chicago, Chicago, IL 60637. Instrument: Pattern Selection Triggers (63). Manufacturer: Hytec Electronics, Ltd., United Kingdom. Intended Use: See notice at 70 FR 13011, March 17, 2005. Comments: None received. Decision: Approved. No apparatus of equivalent scientific value to the foreign apparatus, for such purposes as it is intended to be used, is